Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/662,532	KOIDE ET AL.
Examiner	Art Unit
Sargon N. Nano	2157

SEARCHED			
Class	Subclass	Date	Examiner
709	203, 204 218	1/29/2007	SN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
East (see attached report)	1/29/2007	SN
Consulted with Pat Salce for 101 issues	2/5/2007	SN

Search Notes

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INTERFERENCE SEARCHED			
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V410-12-0-			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (see attached report)	1/29/2007	SN
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